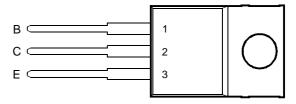
- 80 W at 25°C Case Temperature
- 7 A Continuous Collector Current
- 10 A Peak Collector Current
- Maximum V_{CE(sat)} of 2 V at I_C = 5 A
- I_{CEX(sus)} 7 A at rated V_{(BR)CEO}

TO-220 PACKAGE (TOP VIEW)



Pin 2 is in electrical contact with the mounting base.

MDTRACA

absolute maximum ratings at 25°C case temperature (unless otherwise noted)

RATING			VALUE	UNIT
	TIP150		300	
Collector-base voltage (I _E = 0)	TIP151	V_{CBO}	350	V
	TIP152		400	
	TIP150		300	
Collector-emitter voltage (I _B = 0)	TIP151	V_{CEO}	350	V
	TIP152		400	
Emitter-base voltage			8	V
Continuous collector current			7	Α
Peak collector current (see Note 1)			10	Α
Continuous base current			1.5	Α
Continuous device dissipation at (or below) 25°C case temperature (see Note 2)			80	W
Continuous device dissipation at (or below) 25°C free air temperature (see Note 3)			2	W
Operating junction temperature range			-65 to +150	°C
Storage temperature range			-65 to +150	°C
Lead temperature 3.2 mm from case for 10 seconds			T _L 260	

NOTES: 1. This value applies for $t_p \le 5$ ms, duty cycle $\le 10\%$.

- 2. Derate linearly to 150°C case temperature at the rate of 0.64 W/°C.
- 3. Derate linearly to 150°C $\,$ free air temperature at the rate of 16 mW/°C.



TIP150, TIP151, TIP152 NPN SILICON POWER DARLINGTONS

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electrical characteristics at 25°C case temperature

	PARAMETER		TEST CONDITION	NS	MIN	TYP	MAX	UNIT
V _{(BR)CBO}	Collector-base breakdown voltage	I _C = 1 mA	I _E = 0	TIP150 TIP151	300 350			V
	breakdown voltage			TIP152	400			
	V _{(BR)CEO} Collector-emitter breakdown voltage			TIP150	300			
V _{(BR)CEO}		$I_C = 10 \text{ mA}$	$I_B = 0$	TIP151	350			V
2. Sando III. Tollago	(see Note 4)		TIP152	400				
	Collector-emitter ICEO cut-off current	V _{CE} = 300 V	$I_B = 0$	TIP150			250	
I _{CEO}		$V_{CE} = 350 \text{ V}$	$I_B = 0$	TIP151			250	μΑ
	out on ourrent	V _{CE} = 400 V	$I_B = 0$	TIP152			250	
I _{CEX(sus)}	Collector-emitter sustaining current	$V_{CLAMP} = V_{(BR)CEO}$			7			Α
I _{EBO}	Emitter cut-off current	V _{EB} = 8 V	I _C = 0				15	mA
	Forward current	V _{CE} = 5 V	I _C = 2.5 A		150			
h_{FE}	transfer ratio	V _{CE} = 5 V	$I_C = 5 A$	(see Notes 4 and 5)	50			
	transier ratio	V _{CE} = 5 V	$I_C = 7 A$		15			
	Collector-emitter	I _B = 10 mA	I _C = 1 A				1.5	
$V_{CE(sat)}$	saturation voltage	$I_B = 100 \text{ mA}$	$I_C = 2 A$	(see Notes 4 and 5)			1.5	V
	Saturation voitage	$I_B = 250 \text{ mA}$	$I_C = 5 A$				2	
V	Base-emitter	I _B = 100 mA	I _C = 2 A	(see Notes 4 and 5)			2.2	V
V _{BE(sat)} saturation	saturation voltage	$I_B = 250 \text{ mA}$	$I_C = 5 A$				2.3	V
V _{EC}	Parallel diode forward voltage	I _E = 7 A	I _B = 0	(see Notes 4 and 5)			3.5	V
h _{fe}	Small signal forward current transfer ratio	V _{CE} = 5 V	I _C = 0.5 A	f = 1 kHz	200			
h _{fe}	Small signal forward current transfer ratio	V _{CE} = 5 V	I _C = 0.5 A	f = 1 MHz	10			
C _{ob}	Output capacitance	V _{CB} = 10 V	I _E = 0	f = 1 MHz			100	pF

NOTES: 4. These parameters must be measured using pulse techniques, $t_p = 300 \mu s$, duty cycle $\leq 2\%$.

thermal characteristics

PARAMETER			TYP	MAX	UNIT
$R_{\theta JC}$	Junction to case thermal resistance			1.56	°C/W
$R_{\theta JA}$	Junction to free air thermal resistance			62.5	°C/W
$C_{\theta C}$	Thermal capacitance of case		0.9		J/°C

inductive-load-switching characteristics at 25°C case temperature

PARAMETER		ARAMETER TEST CONDITIONS †			MIN	TYP	MAX	UNIT
t _{sv}	Voltage storage time					3.9		μs
t _{si}	Current storage time	$I_C = 5 \text{ A}$ $V_{(clamp)} = V_{(BR)CEO}$			4.7		μs	
t _{rv}	Voltage transition time		$I_{B(on)} = 250 \text{ mA}$	$R_{BE} = 47 \Omega$		1.2		μs
t _{ti}	Current transition time					1.2		μs
t _{xo}	Cross-over time				2.0		μs	

 $^{^{\}dagger} \ \ \mbox{Voltage and current values shown are nominal; exact values vary slightly with transistor parameters.}$

PRODUCT INFORMATION

^{5.} These parameters must be measured using voltage-sensing contacts, separate from the current carrying contacts.

PARAMETER MEASUREMENT INFORMATION

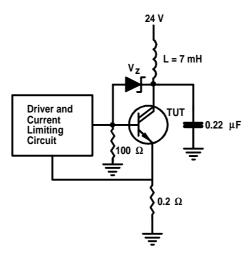


Figure 1. Functional Test Circuit

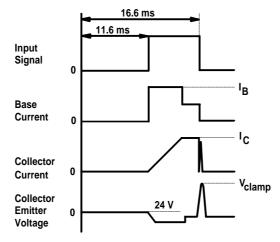


Figure 2. Functional Test Waveforms

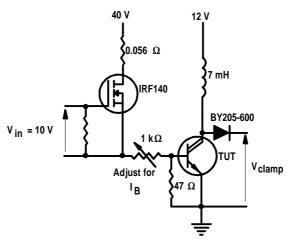


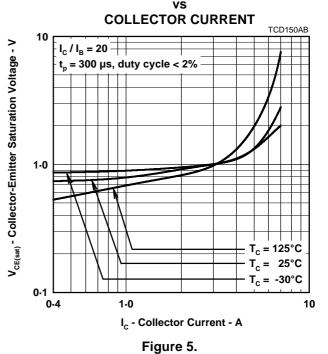
Figure 3. Switching Test Circuit



TYPICAL CHARACTERISTICS

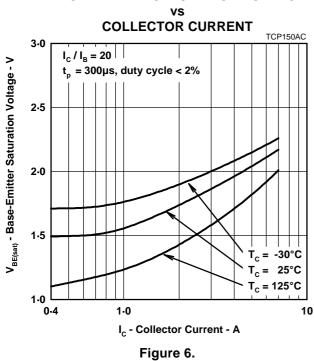
TYPICAL DC CURRENT GAIN VS COLLECTOR CURRENT $t_{\rm C} = 5 \text{ V}$ $t_{\rm p} = 300 \, \mu \text{s}, \, \text{duty cycle} < 2\%$ $t_{\rm p} = 300 \, \mu \text{s}, \, \text{duty cycle} < 2\%$ $t_{\rm c} = -30^{\circ}\text{C}$ $t_{\rm c} = -30^{\circ}\text{C}$ $t_{\rm c} = -30^{\circ}\text{C}$

COLLECTOR-EMITTER SATURATION VOLTAGE

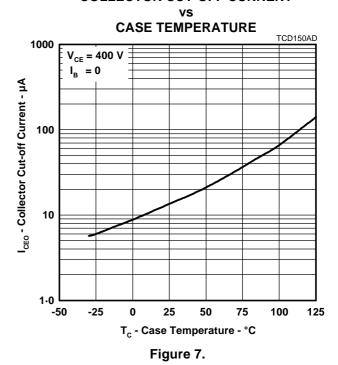


BASE-EMITTER SATURATION VOLTAGE

Figure 4.

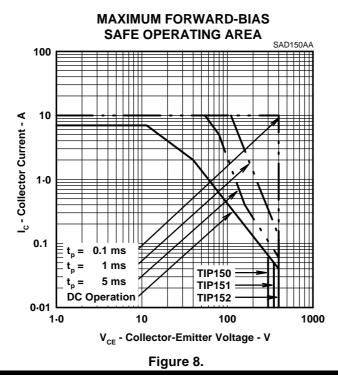


COLLECTOR CUT-OFF CURRENT



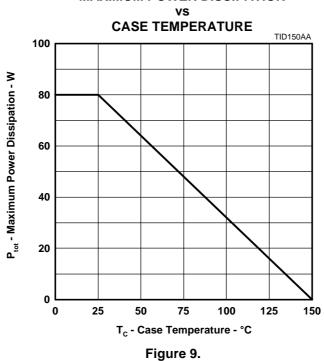
PRODUCT INFORMATION

MAXIMUM SAFE OPERATING REGIONS



THERMAL INFORMATION

MAXIMUM POWER DISSIPATION





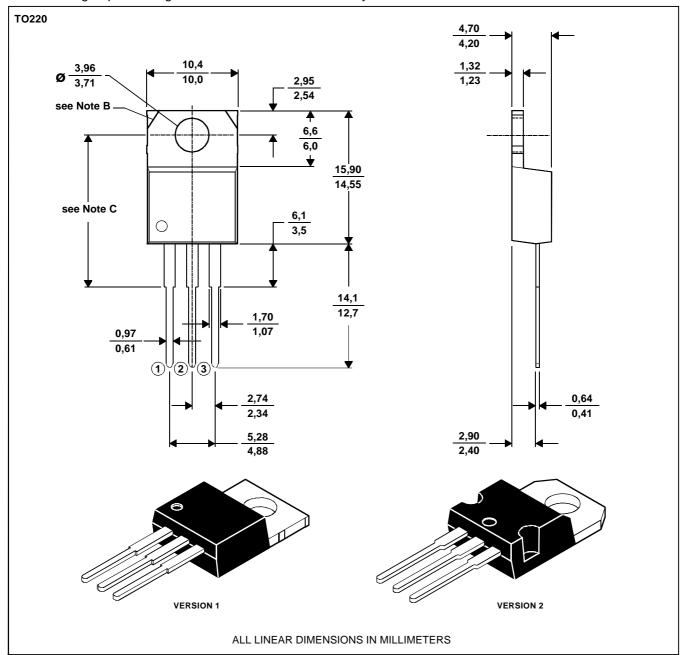
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MECHANICAL DATA

TO-220

3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



NOTES: A. The centre pin is in electrical contact with the mounting tab.

- B. Mounting tab corner profile according to package version.
- C. Typical fixing hole centre stand off height according to package version. Version 1, 18.0 mm. Version 2, 17.6 mm.

MDXXBE

PRODUCT INFORMATION

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